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Lateral Alignment of Epitaxial Quantum Dots





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Introduction

The unique success story of semiconductor physics and technology relies on the ability to highly integrate micro- and nanometer sized functional units on a single chip. Within the last years epitaxial quantum dots have become such functional units and moved to the forefront of cutting edge research to study the exciting physics of single quantum structures and to fathom their tremendous potential for device applications.

Quantum dots constitute a natural template to construct refined artificial matter, such as artificial atoms, molecules and possibly artificial crystals with entirely new electronic and optical properties. However, the full advantage of their unique properties can be exploited, only, if a controlled positioning or growth of the quantum dots inside a more complex device structure or a precise coupling between the quantum dots and a macroscopic periphery can be achieved. The prime task of this book is to review recent techniques, which allow the controlled positioning and lateral alignment of quantum dots on standard substrate surfaces.

The alignment techniques range from pure self-ordering mechanisms to advanced quantum dot growth on patterned substrates. In the former case, growth conditions, substrate orientations and layer sequences are optimized to achieve a high degree of lateral ordering. In the latter case, the nucleation centers of the quantum dots are defined by appropriate pre-patterning of the substrate surfaces. This approach allows for an absolute positioning of the quantum dots relative to marker structures, which are necessary to define a device at the position of the quantum dot in subsequent processing steps.

While this book clearly documents the great advance made in controlling the spatial position of quantum dots, there remain huge challenges that need rigorous tackling in future years. One of the biggest problems is the nonresonant energy spectrum of quantum dot ensembles, even if they are located in an apparently perfectly ordered array. The reason is that each quantum dot is slightly different in size, shape and composition and therefore emits a photon with a different energy. The question of "How identical are nanostructures and can we create identical nanostructures?" addresses many fields of today's integrative nanotechnologies and is not inherent to quantum dots. For quantum dots, a solution might be a self-limiting growth mechanism or the manipulation of individual quantum dots after growth. Part I of this book concentrates on the lateral self-alignment of epitaxial quantum dots. This self-alignment is realized by choosing appropriate growth conditions and special substrate surfaces. The self-alignment on a short range scale is exploited to create compact lateral quantum dot molecules. By stacking multiple quantum dot layers pronounced lateral ordering on a medium range scale is accomplished. The underlying growth mechanisms governing these phenomena are described and reviewed in detail in the first part of the book.

In the second Part the aim is to control the absolute lateral position of quantum dots on a long-range scale. Such long-range ordered quantum dot arrays might be useful for a high integration of single quantum dot devices, or to realize one, two, and three dimensional quantum dot crystals. Part II demonstrates that such artificial crystals can be created with high structural integrity and excellent optical quality. However, at the present stage the distances between quantum dots are too large as to observe new electronic band structures.

My gratitude goes to all authors having composed the 26 chapters of this book. It took more than two years to put together this work, but I am sure the effort was worthwhile and the book will serve as a helpful platform to understand the many fundamental questions of quantum dot growth as well as to further our efforts to eventually integrate single quantum dots on a single chip.

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